

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SHEN ET AL.	
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*	B	US-6,671,322	12-2003	Vetro et al.	375/240.16
*	C	US-2003/0021345 1/2003	09-2004	Brusewitz	375/240.18
*	D	US-6,487,249 11/2002	10-1998	Kim et al.	375/240.21
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